

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Praveen Parvathala

Title: FUNCTIONAL RANDOM INSTRUCTION TESTING (FRIT) METHOD FOR COMPLEX DEVICES SUCH AS MICROPROCESSORS

Docket No.: 80107.051US1

Filed: July 31, 2001

Examiner: John J. Tabone



Serial No.: 09/917,661

Due Date: July 14, 2004

Group Art Unit: 2133

Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

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We are transmitting herewith the following attached items (as indicated with an "X"):

- ☒ A return postcard.
- ☒ An Amendment and Response under 37 CFR 1.111 (16 Pages).

If not provided for in a separate paper filed herewith, Please consider this a PETITION FOR EXTENSION OF TIME for sufficient number of months to enter these papers and please charge any additional fees or credit overpayment to Deposit Account No. 50-2359.

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CERTIFICATE UNDER 37 CFR 1.8: The undersigned hereby certifies that this correspondence is being deposited with the United States Postal Service with sufficient postage as first class mail, in an envelope addressed to: Mail Stop Amendment, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on this 15 day of June, 2004.

Emily Bates
Name

Emily Bates
Signature

(GENERAL)



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PATENT

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Applicant has reviewed the Office Action mailed on April 14, 2004. Please amend the above-identified patent application as follows.